

Raynald Gauvin

List of Publications by Year in descending order

Source: <https://exaly.com/author-pdf/9915035/publications.pdf>

Version: 2024-02-01

115
papers

1,114
citations

471509

17
h-index

477307

29
g-index

119
all docs

119
docs citations

119
times ranked

1375
citing authors

#	ARTICLE	IF	CITATIONS
1	Silicon doped carbon nanotubes as high energy anode for lithium-ion batteries. Materials Today Communications, 2022, 30, 103158.	1.9	8
2	Tetragonal reconstruction and monoclinic variants rearrangement during heat treatment in zirconia. Journal of the American Ceramic Society, 2022, 105, 5436-5447.	3.8	3
3	Phase differentiation based on x-ray energy spectrum correlation with an energy dispersive spectrometer (EDS). Ultramicroscopy, 2022, 238, 113534.	1.9	2
4	Structural Study of Sulfur-Added Carbon Nanohorns. Materials, 2022, 15, 3412.	2.9	1
5	Extraction of 3D quantitative maps using EDS-STEM tomography and HAADF-EDS bimodal tomography. Ultramicroscopy, 2021, 220, 113166.	1.9	0
6	Plasmon-Enhanced Hydrogenation of 1-Dodecene and Toluene Using Ruthenium-Coated Gold Nanoparticles. ACS Applied Nano Materials, 2021, 4, 1596-1603.	5.0	6
7	Scanning Electron Microscopy versus Transmission Electron Microscopy for Material Characterization: A Comparative Study on High-Strength Steels. Scanning, 2021, 2021, 1-19.	1.5	13
8	High-Resolution Electron Microscopy Analysis of Malaria Hemozoin Crystals Reveals New Aspects of Crystal Growth and Elemental Composition. Crystal Growth and Design, 2021, 21, 5521-5533.	3.0	5
9	Enhancing Singlet Oxygen Photocatalysis with Plasmonic Nanoparticles. ACS Applied Materials & Interfaces, 2021, 13, 35606-35616.	8.0	22
10	The f-ratio model for quantitative X-ray microanalysis. Talanta, 2021, 235, 122765.	5.5	5
11	Study of the Peak to Background (P/B) Method Behavior as a Function of Take-Off Angle, Tilt Angle, Particle Size, and Beam Energy. Scanning, 2021, 2021, 1-7.	1.5	1
12	In Situ and In Operando Techniques to Study Li-Ion and Solid-State Batteries: Micro to Atomic Level. Inorganics, 2021, 9, 85.	2.7	5
13	Improvement of the energy resolution of energy dispersive spectrometers (EDS) using Richardson's "Lucy deconvolution. Ultramicroscopy, 2020, 209, 112886.	1.9	7
14	Investigation of the Effect of Magnification, Accelerating Voltage, and Working Distance on the 3D Digital Reconstruction Techniques. Scanning, 2020, 2020, 1-9.	1.5	1
15	Core hole screened electron energy loss calculations of beam damaged lithium fluoride. Ultramicroscopy, 2020, 219, 113126.	1.9	0
16	Direct observation of lithium metal dendrites with ceramic solid electrolyte. Scientific Reports, 2020, 10, 18410.	3.3	45
17	The Impact of Chemical Bonding on Mass Absorption Coefficients of Soft X-rays. Microscopy and Microanalysis, 2020, 26, 741-749.	0.4	2
18	Secondary Fluorescence of 3D Heterogeneous Materials Using a Hybrid Model. Microscopy and Microanalysis, 2020, 26, 484-496.	0.4	2

#	ARTICLE	IF	CITATIONS
19	A hydrodynamic approach to electron beam imaging using a Bloch wave representation. Ultramicroscopy, 2020, 212, 112979.	1.9	1
20	Multivariate Statistical Analysis on a SEM/EDS Phase Map of Rare Earth Minerals. Scanning, 2020, 2020, 1-11.	1.5	7
21	Inverse modeling for quantitative X-ray microanalysis applied to 2D heterogeneous materials. Ultramicroscopy, 2020, 219, 113117.	1.9	2
22	Microstructure evolution of Inconel 738 fabricated by pulsed laser powder bed fusion. Progress in Additive Manufacturing, 2019, 4, 97-107.	4.8	30
23	Using Deep Learning to Deconvolute Complex Spectra for Hyperspectral Imaging Applications. Microscopy and Microanalysis, 2019, 25, 178-179.	0.4	0
24	EELS Monitoring of Beam-Induced Dynamic Transformation of Lithium Materials at 30 keV. Microscopy and Microanalysis, 2019, 25, 2168-2169.	0.4	0
25	Extending Monte Carlo Simulations of Electron Microscopy Images and Hyperspectral Images in a User-Friendly Framework. Microscopy and Microanalysis, 2019, 25, 222-223.	0.4	2
26	The Impact of Phase on Mass Absorption Coefficients Using Soft X-ray Emission Spectrometry. Microscopy and Microanalysis, 2019, 25, 250-251.	0.4	0
27	Wave-packet numerical investigation of thermal diffuse scattering: A time-dependent quantum approach to electron diffraction simulations. Micron, 2019, 126, 102737.	2.2	1
28	<i>In-Situ</i> Characterization of Lithium Native Passivation Layer in A High Vacuum Scanning Electron Microscope. Microscopy and Microanalysis, 2019, 25, 866-873.	0.4	5
29	The f-ratio quantification method applied to standard minerals with a cold field emission SEM/EDS. Talanta, 2019, 204, 213-223.	5.5	3
30	Secondary Fluorescence Correction for Characteristic and Bremsstrahlung X-Rays Using Monte Carlo X-ray Depth Distributions Applied to Bulk and Multilayer Materials. Microscopy and Microanalysis, 2019, 25, 92-104.	0.4	8
31	The <i>f</i> -Ratio Quantification Method for X-ray Microanalysis Applied to Mg-Al-Zn Alloys. Microscopy and Microanalysis, 2019, 25, 58-69.	0.4	4
32	In situ observation of solid electrolyte interphase evolution in a lithium metal battery. Communications Chemistry, 2019, 2, .	4.5	52
33	Electron energy-loss spectroscopy (EELS) with a cold-field emission scanning electron microscope at low accelerating voltage in transmission mode. Ultramicroscopy, 2019, 203, 21-36.	1.9	17
34	Microstructure and mechanical property connections for a punched non-oriented electrical steel lamination. Materials Science & Engineering A: Structural Materials: Properties, Microstructure and Processing, 2018, 725, 456-465.	5.6	15
35	Secondary Fluorescence Correction of 3D Heterogeneous Materials for Quantitative X-ray Microanalysis. Microscopy and Microanalysis, 2018, 24, 778-779.	0.4	0
36	Low Voltage Analytical Possibilities in a Scanning Electron Microscope in Transmission Mode at 30 kV: EDS, EELS and CBED at the Nanoscale. Microscopy and Microanalysis, 2018, 24, 2036-2037.	0.4	0

#	ARTICLE	IF	CITATIONS
37	The Joy of Nanoscale Imaging and Spectroscopy in a Low Accelerating Voltage Scanning Transmitted Electron Microscope. <i>Microscopy and Microanalysis</i> , 2018, 24, 640-641.	0.4	0
38	In Situ Scanning Electron Microscopy Detection of Carbide Nature of Dendrites in Li ⁺ Polymer Batteries. <i>Nano Letters</i> , 2018, 18, 7583-7589.	9.1	86
39	Nanoscale Lithium Quantification in Li _{1-x} Ni _y Co _{1-y} MnZrO ₂ as Cathode for Rechargeable Batteries. <i>Scientific Reports</i> , 2018, 8, 17575.	3.3	32
40	Monte Carlo Simulation of Surface Semi-Spherical Inclusions Using MC X-ray. <i>Microscopy and Microanalysis</i> , 2018, 24, 740-741.	0.4	0
41	EELS Analysis of Bulk Plasmon Harmonics of Aluminium at 30 keV. <i>Microscopy and Microanalysis</i> , 2018, 24, 464-465.	0.4	3
42	The Standard-based f-ratio Quantitative X-Ray Microanalysis Method for a Field Emission SEM. <i>Microscopy and Microanalysis</i> , 2018, 24, 732-733.	0.4	1
43	Influence of Substrate Characteristics on Single Ti Splat Bonding to Ceramic Substrates by Cold Spray. <i>Journal of Thermal Spray Technology</i> , 2018, 27, 1011-1024.	3.1	12
44	Fabrication of Crack-Free Nickel-Based Superalloy Considered Non-Weldable during Laser Powder Bed Fusion. <i>Materials</i> , 2018, 11, 1288.	2.9	47
45	Hollow silica capsules for amphiphilic transport and sustained delivery of antibiotic and anticancer drugs. <i>RSC Advances</i> , 2018, 8, 24883-24892.	3.6	14
46	My Joy of Research in SEM. <i>Microscopy and Microanalysis</i> , 2018, 24, 602-603.	0.4	1
47	In Situ TEM Investigation of Electron Irradiation Induced Metastable States in Lithium-Ion Battery Cathodes: Li ₂ FeSiO ₄ versus LiFePO ₄ . <i>ACS Applied Energy Materials</i> , 2018, 1, 3180-3189.	5.1	20
48	Use of an Annular Silicon Drift Detector (SDD) Versus a Conventional SDD Makes Phase Mapping a Practical Solution for Rare Earth Mineral Characterization. <i>Microscopy and Microanalysis</i> , 2018, 24, 238-248.	0.4	8
49	The qualitative f-ratio method applied to electron channelling-induced x-ray imaging with an annular silicon drift detector in a scanning electron microscope in the transmission mode. <i>Journal of Microscopy</i> , 2017, 267, 288-298.	1.8	3
50	Growth modes for monoclinic yttria-stabilized zirconia during the martensitic transformation. <i>Journal of the American Ceramic Society</i> , 2017, 100, 4874-4883.	3.8	13
51	Quantification of Thin Specimens in a Scanning Transmission Electron Microscope at Low Accelerating Voltage using the f-ratio Method. <i>Microscopy and Microanalysis</i> , 2017, 23, 236-237.	0.4	1
52	The Effect of Submicron Second-Phase Particles on the Rate of Grain Refinement in a Copper-Oxygen Alloy During Cold Spray. <i>Journal of Thermal Spray Technology</i> , 2017, 26, 1509-1516.	3.1	18
53	Mapping Data with Heavily Overlapped Spectral Features. <i>Microscopy and Microanalysis</i> , 2017, 23, 216-217.	0.4	0
54	Open Source Software for Quantitative X-ray Microanalysis: openMicroanalysis. <i>Microscopy and Microanalysis</i> , 2017, 23, 234-235.	0.4	0

#	ARTICLE	IF	CITATIONS
55	The Fluorescence Correction of Multilayer Materials for Quantitative X-ray Microanalysis. <i>Microscopy and Microanalysis</i> , 2017, 23, 218-219.	0.4	1
56	Low Accelerating Voltage Scanning Transmitted Electron Microscope: Imaging, Diffraction, X-ray Microanalysis, and Electron Energy-Loss Spectroscopy at the Nanoscale. <i>Microscopy and Microanalysis</i> , 2017, 23, 528-529.	0.4	2
57	The f-ratio Quantification Method for X-ray Microanalysis with a Field Emission SEM Applied to Multi-Elements Specimen. <i>Microscopy and Microanalysis</i> , 2017, 23, 1046-1047.	0.4	4
58	Thermal Stability of Cryomilled Al-Mg-Er Powders. <i>Journal of Nanomaterials</i> , 2017, 2017, 1-17.	2.7	2
59	High Spatial Resolution Spectroscopy in a FE-SEM: X-ray Microanalysis and Electron Energy-Loss Spectroscopy. <i>Microscopy and Microanalysis</i> , 2017, 23, 1044-1045.	0.4	2
60	About the contrast of Al_2Cu precipitates in bulk Al-Cu-Li alloys in reflection mode with a field-emission scanning electron microscope at low accelerating voltage. <i>Journal of Microscopy</i> , 2017, 268, 107-118.	1.8	7
61	X-ray Emission From Thin Films on a Substrate - Experiments and Simulation. <i>Microscopy and Microanalysis</i> , 2016, 22, 400-401.	0.4	4
62	Determination of Soft X-ray Emission Spectroscopy Parameters using Experimental Data for Quantitative Microanalysis. <i>Microscopy and Microanalysis</i> , 2016, 22, 408-409.	0.4	4
63	Deformation Analysis of Forsterite Olivine Using Electron Channeling Contrast Imaging and Electron Backscatter Diffraction. <i>Microscopy and Microanalysis</i> , 2016, 22, 1792-1793.	0.4	2
64	Can we detect Li K X-ray in lithium compounds using energy dispersive spectroscopy?. <i>Scanning</i> , 2016, 38, 571-578.	1.5	77
65	X-ray Microanalysis Phase Map on Rare Earth Minerals with a Conventional and an Annular Silicon Drift Detector. <i>Microscopy and Microanalysis</i> , 2016, 22, 96-97.	0.4	1
66	Monte Carlo Simulations of Electron Energy-Loss Spectra with the Addition of Fine Structure from Density Functional Theory Calculations. <i>Microscopy and Microanalysis</i> , 2016, 22, 219-229.	0.4	1
67	On Rotation Contour Contrast in Hot-Compressed Magnesium Alloys in a Scanning Electron Microscope. <i>Metallography, Microstructure, and Analysis</i> , 2016, 5, 188-195.	1.0	1
68	A universal equation for computing the beam broadening of incident electrons in thin films. <i>Ultramicroscopy</i> , 2016, 167, 21-30.	1.9	16
69	Dark-Field Imaging based on Post-Processing of Electron Backscatter Diffraction Patterns in a Scanning Electron Microscope. <i>Microscopy and Microanalysis</i> , 2015, 21, 2031-2032.	0.4	1
70	Characterization of Hot-Compressed Magnesium Alloys in a Scanning Electron Microscope. <i>Microscopy and Microanalysis</i> , 2015, 21, 599-600.	0.4	0
71	Rotation Axes Analysis of Deformed Magnesium Using Electron Backscatter Diffraction and Rotation Contour Contrast Reconstruction. <i>Microscopy and Microanalysis</i> , 2015, 21, 2379-2380.	0.4	0
72	Origins and Contrast of the Electron Signals at Low Accelerating Voltage and with Energy-Filtering in the FE-SEM for High Resolution Imaging. <i>Microscopy and Microanalysis</i> , 2015, 21, 705-706.	0.4	2

#	ARTICLE	IF	CITATIONS
73	Characterization of Advanced Nanomaterials for Lithium Ion Batteries Cathodes. Microscopy and Microanalysis, 2015, 21, 677-678.	0.4	1
74	High Spatial Resolution Quantification X-ray Microanalysis in a Field Emission Scanning Electron Microscope with an Annular Silicon Drift Detector. Microscopy and Microanalysis, 2015, 21, 2359-2360.	0.4	1
75	Rotation axes analysis of deformed magnesium based on rotation contour contrast in a scanning electron microscope. Ultramicroscopy, 2015, 154, 42-48.	1.9	6
76	Microstructure and Mechanical Properties of Ti Cold-Spray Splats Determined by Electron Channeling Contrast Imaging and Nanoindentation Mapping. Microscopy and Microanalysis, 2015, 21, 570-581.	0.4	38
77	Dark-field imaging based on post-processed electron backscatter diffraction patterns of bulk crystalline materials in a scanning electron microscope. Ultramicroscopy, 2015, 148, 123-131.	1.9	14
78	High Resolution Imaging in the Field Emission Scanning Electron Microscope at Low Accelerating Voltage and with Energy-Filtration of the Electron Signals. Microscopy and Microanalysis, 2014, 20, 16-17.	0.4	0
79	Spatial Distribution of Light Scattering and Absorption Interactions with TiO ₂ - Nanoparticles from Monte Carlo and Generalized-Multiparticle-Mie based Simulations for Dye-Sensitized Solar Cell Analysis and Optimization. Microscopy and Microanalysis, 2014, 20, 548-549.	0.4	0
80	Microstructure Refinement of Cold-Sprayed Copper Investigated By Electron Channeling Contrast Imaging. Microscopy and Microanalysis, 2014, 20, 1499-1506.	0.4	22
81	X-Ray Microanalysis with High Spatial Resolution and High Counts Rate with a State of the Art Field Emission Scanning Electron Microscope. Microscopy and Microanalysis, 2014, 20, 650-651.	0.4	1
82	Microstructural Characterization of Mg-0.3Al-0.2Ca Alloy Using Ion Milling Surface Preparation Technique. Metallography, Microstructure, and Analysis, 2014, 3, 257-262.	1.0	3
83	Magnetic domain structure and crystallographic orientation of electrical steels revealed by a forescatter detector and electron backscatter diffraction. Ultramicroscopy, 2014, 142, 40-49.	1.9	25
84	Ionic Liquid Used for Charge Compensation for High-Resolution Imaging and Analysis in the FE-SEM. Microscopy and Microanalysis, 2014, 20, 38-39.	0.4	5
85	Transmission Electron Forward Scattered Diffraction and Low Voltage SEM/STEM Characterization of Binder-Free TiO ₂ Electrodes. Microscopy and Microanalysis, 2014, 20, 492-493.	0.4	1
86	X-ray Quantitative Microanalysis Maps across Interfaces of a Cu-Al Roll Bonded Laminate with an Annular Silicon Drift Detector. Microscopy and Microanalysis, 2014, 20, 676-677.	0.4	1
87	Electron Channeling Contrast Observations in Deformed Magnesium Alloys. Microscopy and Microanalysis, 2014, 20, 1452-1453.	0.4	1
88	Magnetic Domain Structure and Crystal Orientation Revealed by a Forescatter Detector and Electron Backscatter Diffraction.. Microscopy and Microanalysis, 2014, 20, 1458-1459.	0.4	0
89	Sliding-induced Microstructure of Cold-Sprayed Copper Coating Observed by Electron Channeling Contrast Imaging. Microscopy and Microanalysis, 2014, 20, 2104-2105.	0.4	3
90	Evaluation of strain rate sensitivity by constant load nanoindentation. Journal of Materials Science, 2012, 47, 7189-7200.	3.7	51

#	ARTICLE	IF	CITATIONS
91	What Remains to Be Done to Allow Quantitative X-Ray Microanalysis Performed with EDS to Become a True Characterization Technique?. Microscopy and Microanalysis, 2012, 18, 915-940.	0.4	26
92	Consolidation of Al ₂ O ₃ /Al Nanocomposite Powder by Cold Spray. Journal of Thermal Spray Technology, 2011, 20, 275-284.	3.1	31
93	Nanocrystalline TiO ₂ thin film electrodes for dye-sensitized solar cell applications. Jom, 2009, 61, 52-57.	1.9	18
94	Thermal stability of SrFeO ₃ /Al ₂ O ₃ thin films: Transmission electron microscopy study and conductometric sensing response. Journal of Applied Physics, 2008, 104, .	2.5	13
95	A Universal Equation for the Emission Range of X Rays from Bulk Specimens. Microscopy and Microanalysis, 2007, 13, 354-357.	0.4	8
96	Transmission electron microscopy investigation of interfacial reactions between SrFeO ₃ thin films and silicon substrates. Journal of Materials Research, 2007, 22, 76-88.	2.6	0
97	Quantitative X-Ray Microanalysis of Heterogeneous Materials Using Monte Carlo Simulations. Mikrochimica Acta, 2006, 155, 75-81.	5.0	12
98	Win X-ray: A New Monte Carlo Program that Computes X-ray Spectra Obtained with a Scanning Electron Microscope. Microscopy and Microanalysis, 2006, 12, 49-64.	0.4	87
99	X-ray microanalysis of real materials using Monte Carlo simulations. Surface and Interface Analysis, 2005, 37, 875-886.	1.8	19
100	Introduction: Characterization of Nonconductive Materials. Microscopy and Microanalysis, 2004, 10, 669-669.	0.4	0
101	X-Ray Microanalysis of Real Materials Using Monte Carlo Simulations. Mikrochimica Acta, 2004, 145, 41-47.	5.0	7
102	Possibility of charge contrast imaging of polymeric materials. Scanning, 2003, 25, 240-242.	1.5	5
103	Contrast of Multilayered Structures in a Field Emission Gun Scanning Electron Microscope. Microscopy and Microanalysis, 2003, 9, 988-989.	0.4	0
104	On the Contrast and Resolution of Secondary and Backscattered Electron Images in a FE-SEM. Microscopy and Microanalysis, 2003, 9, 970-971.	0.4	2
105	Spatial Resolution Limits for X-ray Microanalysis of Bulk Samples. Microscopy and Microanalysis, 2003, 9, 536-537.	0.4	1
106	Win X-ray, The Monte Carlo Program for X-ray Microanalysis in the Scanning Electron Microscope. Microscopy and Microanalysis, 2003, 9, 32-33.	0.4	7
107	On the Simulation of True EDS X-Ray Spectra. Microscopy and Microanalysis, 2002, 8, 430-431.	0.4	0
108	Physics of Low Voltage Scanning Electron Microscopy. Microscopy and Microanalysis, 2002, 8, 116-117.	0.4	13

#	ARTICLE	IF	CITATIONS
109	X-Ray Microanalysis of a Coated Non-Conductive Specimen: Monte Carlo Simulation. Microscopy and Microanalysis, 2002, 8, 1462-1463.	0.4	0
110	SEM-EDS Quantitative Analysis of Aerosols $\leq 80\text{nm}$: Impacts on Atmospheric Aerosol Characterization Campaigns. Microscopy and Microanalysis, 2002, 8, 1482-1483.	0.4	3
111	Evaluation of Current Standardless Quantitative Analysis Programs using Energy Dispersive Spectrometry in the SEM. Microscopy and Microanalysis, 2002, 8, 1470-1471.	0.4	0
112	Quantitative X-Ray Microanalysis with a Low Voltage Scanning Electron Microscope. Microscopy and Microanalysis, 2002, 8, 1474-1475.	0.4	0
113	Modeling Contrasts in Variable Pressure Scanning Electron Microscopes. Microscopy and Microanalysis, 2002, 8, 452-453.	0.4	0
114	WinX-Ray: A New Monte Carlo Program for the Simulation of X-Ray and Charging Materials. Microscopy and Microanalysis, 2002, 8, 1498-1499.	0.4	10
115	A method to measure the effective gas path length in the environmental or variable pressure scanning electron microscope. Scanning, 2002, 24, 171-174.	1.5	8